

CY7C1061AV33

16-Mbit (1 M × 16) Static RAM

Features

- High speed □ t_{AA} = 10 ns
- Low active power □ 990 mW (max)
- Operating voltages of 3.3 ± 0.3 V
- 2.0 V data retention
- Automatic power down when deselected
- TTL compatible inputs and outputs
- Easy memory expansion with \overline{CE}_1 and CE_2 features
- Available in Pb-free and non Pb-free 54-pin TSOP II package and non Pb-free 60-ball fine-pitch ball grid array (FBGA) package

Functional Description

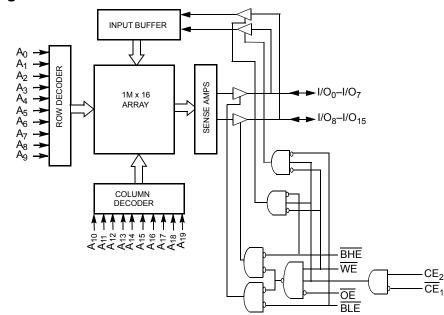
The CY7C1061AV33 is a high performance CMOS Static RAM organized as 1,048,576 words by 16 bits.

To write to the device, enable the chip (\overline{CE}_1 LOW and CE_2 HIGH) while forcing the Write Enable (\overline{WE}) input LOW. If Byte Low Enable (\overline{BLE}) is LOW, then data from I/O pins (I/O₀ through I/O₇), is written into the location specified on the address pins (A₀ through A₁₉). If Byte High Enable (\overline{BHE}) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₉).

To read from the device, enable the chip by taking \overline{CE}_1 LOW and CE_2 HIGH while forcing the Output Enable (\overline{OE}) LOW and the Write Enable (\overline{WE}) HIGH. If Byte Low Enable (\overline{BLE}) is LOW, then data from the memory location specified by the address pins will appear on I/O₀ to I/O₇. If Byte High Enable (\overline{BHE}) is LOW, then data from memory will appear on I/O₈ to I/O₁₅. See Truth Table on page 8 for a complete description of Read and Write modes.

The input/output pins (I/O₀ through I/O₁₅) are placed in a high-impedance state when the device is deselected (\overline{CE}_1 HIGH/CE₂ LOW), the outputs are disabled (\overline{OE} HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or a Write operation is in progress (\overline{CE}_1 LOW, CE₂ HIGH, and \overline{WE} LOW).

Logic Block Diagram



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San Jose, CA 95134-1709 • 408-943-2600 Revised April 11, 2011



CY7C1061AV33

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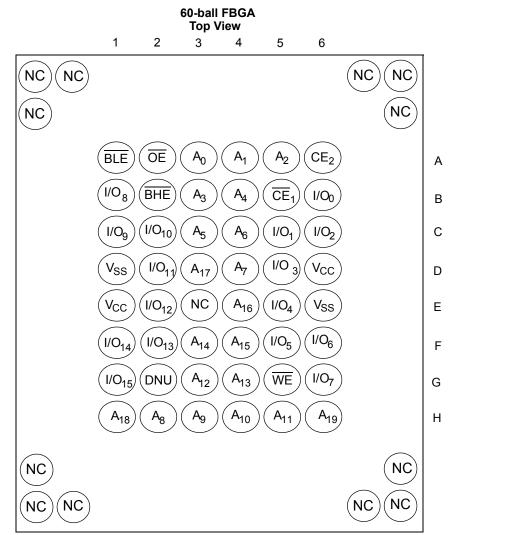
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Selection Guide

		-10	Unit
Maximum Access Time		10	ns
Maximum Operating Current	Commercial	275	mA
	Industrial	275	
Maximum CMOS Standby Current	Commercial/Industrial	50	mA

Pin Configurations ^[1, 2]



54	4-pin T (Top \	'SOP I View)	I
10 10 10 10 10 10 10 10 10 10	1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27	54 53 52 51 50 49 48 47 46 45 44 43 41 40 39 38 37 36 35 34 33 32 31 30 29 28	1 1 1 1 1 1 1 1 1 1 1 1 1 1

Notes

- 1. NC pins are not connected on the die.
- 2. DNU (Do Not Use) pins have to be left floating or tied to VSS to ensure proper operation.



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. These user guidelines are not tested.

Storage Temperature	–65 °C to +150 °C
Ambient Temperature with Power Applied	55 °C to +125 °C
Supply Voltage on V_{CC} to Relative GN	D ^[3] –0.5 V to +4.6 V
DC Voltage Applied to Outputs in High Z State ^[3]	
in High Z State [3]	–0.5 V to V _{CC} + 0.5 V

DC Electrical Characteristics

(Over the Operating Range)

Current into Outputs (LOW)...... 20 mA

Operating Range

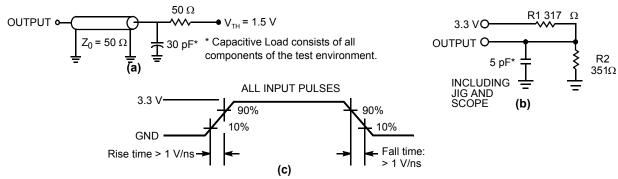
Range	Ambient Temperature	V _{cc}
Commercial	0 °C to +70 °C	$3.3~V\pm0.3~V$
Industrial	–40 °C to +85 °C	

Parameter	Description	Test Condition	-	Unit						
Falameter	Description	Test Condition	Test Conditions				Min		Max	Onit
V _{OH}	Output HIGH Voltage	utput HIGH Voltage I _{OH} = -4.0 mA		2.4	-	V				
V _{OL}	Output LOW Voltage	I _{OL} = 8.0 mA		-	0.4	V				
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	V				
V _{IL}	Input LOW Voltage ^[3]			-0.3	0.8	V				
I _{IX}	Input Leakage Current	$GND \le V_I \le V_{CC}$	$GND \leq V_I \leq V_{CC}$			μA				
I _{OZ}	Output Leakage Current	$GND \leq V_O \leq V_{CC}$, Output Dis	abled	-1	+1	μA				
I _{CC}	V _{CC} Operating Supply Current	V_{CC} = max, f = f _{max} = 1/t _{RC}	V_{CC} = max, f = f _{max} = 1/t _{RC} Commercial		275	mA				
			Industrial	_	275	mA				
I _{SB1}	Automatic CE Power-down Current —TTL Inputs	$ \begin{array}{c} CE_2 \leq V_{IL,} \text{ Max } V_{CC}, \overline{CE} \geq V_I \\ V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, f = f_{ma} \end{array} $	H, x	_	70	mA				
I _{SB2}	Automatic CE Power-down Current —CMOS Inputs	$\begin{array}{l} \underline{CE}_2 \leq 0.3 \text{ V, Max } V_{CC}, \\ \overline{CE} \geq V_{CC} - 0.3 \text{ V,} \\ \overline{V}_{IN} \geq V_{CC} - 0.3 \text{ V,} \\ \text{or } V_{IN} \leq 0.3 \text{ V, } f = 0 \end{array}$	Commercial/ Industrial	_	50	mA				

Capacitance [4]

Parameter	Description	Test Conditions	TSOP II	FBGA	Unit
C _{IN}	Input Capacitance	T _A = 25 °C, f = 1 MHz, V _{CC} = 3.3 V	6	8	pF
C _{OUT}	I/O Capacitance		8	10	pF

AC Test Loads and Waveforms ^[5]



Notes

- V_{IL} (min) = -2.0 V for pulse durations of less than 20 ns.
 Tested initially and after any design or process changes that may affect these parameters.
 Valid SRAM operation does not occur until the power supplies have reached the minimum operating V_{DD} (3.0 V). As soon as 1 ms (T_{power}) after reaching the minimum operating V_{DD}, normal SRAM operation can begin including reduction in V_{DD} to the data retention (V_{CCDR}, 2.0 V) voltage.



AC Switching Characteristics

(Over the Operating Range) [6]

Devenueter	Description	-	-10					
Parameter	Description	Min	Мах	Unit				
Read Cycle								
t _{power}	V _{CC} (typical) to the first access ^[7]	1	-	ms				
t _{RC}	Read Cycle Time	10	-	ns				
t _{AA}	Address to Data Valid	-	10	ns				
t _{OHA}	Data Hold from Address Change	3	-	ns				
t _{ACE}	CE ₁ LOW/CE ₂ HIGH to Data Valid	-	10	ns				
t _{DOE}	OE LOW to Data Valid	-	5	ns				
t _{LZOE}	OE LOW to Low Z	1	_	ns				
t _{HZOE}	OE HIGH to High Z ^[8]	-	5	ns				
t _{LZCE}	CE ₁ LOW/CE ₂ HIGH to Low Z ^[8]	3	_	ns				
t _{HZCE}	CE ₁ HIGH/CE ₂ LOW to High Z ^[8]	-	5	ns				
t _{PU}	CE ₁ LOW/CE ₂ HIGH to Power Up ^[9]	0	_	ns				
t _{PD}	CE ₁ HIGH/CE ₂ LOW to Power Down ^[9]	-	10	ns				
t _{DBE}	Byte Enable to Data Valid	-	5	ns				
t _{LZBE}	Byte Enable to Low Z	1	-	ns				
t _{HZBE}	Byte Disable to High Z	-	5	ns				
Write Cycle [10, 11]								
t _{WC}	Write Cycle Time	10	_	ns				
t _{SCE}	CE ₁ LOW/CE ₂ HIGH to Write End	7	_	ns				
t _{AW}	Address Setup to Write End	7	_	ns				
t _{HA}	Address Hold from Write End	0	_	ns				
t _{SA}	Address Setup to Write Start	0	_	ns				
t _{PWE}	WE Pulse Width	7	_	ns				
t _{SD}	Data Setup to Write End	5.5	_	ns				
t _{HD}	Data Hold from Write End	0	_	ns				
t _{LZWE}	WE HIGH to Low Z ^[8]	3	_	ns				
t _{HZWE}	WE LOW to High Z ^[8]	-	5	ns				
t _{BW}	Byte Enable to End of Write	7	-	ns				

Notes

Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and specified transmission line loads. Test conditions for the Read cycle use output loading shown in (a) of the AC Test Loads and Waveforms ^[5] on page 4, unless 6. specified otherwise.

This part has a voltage regulator that steps down the voltage from 3 V to 2 V internally. t_{power} time must be provided initially before a Read/Write operation is started. t_{H2OE} , t_{H2WE} , t_{H2BE} and t_{L2OE} , t_{L2CE} , t_{U2WE} , t_{L2DE} are specified with a load capacitance of 5 pF as in (b) of AC Test Loads and Waveforms ^[5] on page 4. Transition is measured ±200 mV from steady-state voltage. 7

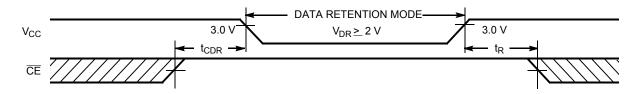
8.

9. These parameters are guaranteed by design and are not tested.

These parameters are guaranteed by design and are not tested.
 The internal Write time of the memory is defined by the overlap of CE₁ LOW (CE₂ HIGH) and WE LOW. Chip enables must be active and WE and byte enables must be LOW to initiate a Write, and the transition of any of these signals can terminate the Write. The input data setup and hold timing should be referenced to the leading edge of the signal that terminates the Write.
 The minimum Write cycle time for Write Cycle No. 2 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.

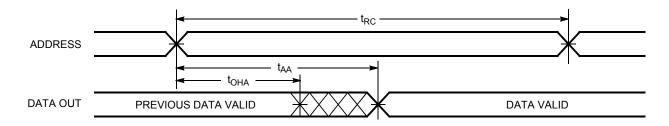


Data Retention Waveform

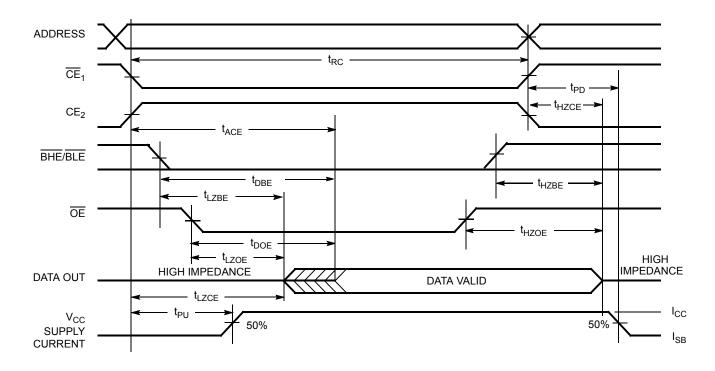


Switching Waveforms

Read Cycle No. 1 (Address Transition Controlled) ^[12, 13]



Read Cycle No. 2 (OE Controlled) ^[13, 14]



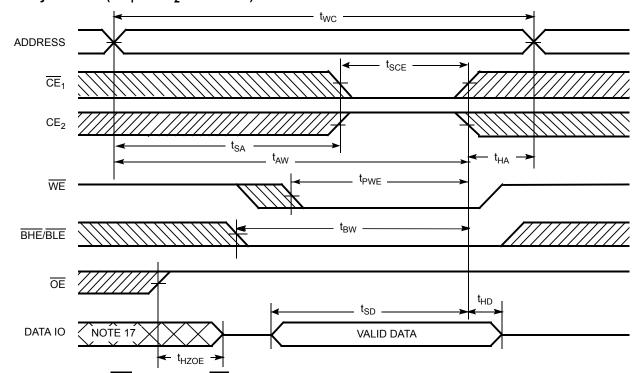
Notes

12. <u>Dev</u>ice is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} or \overline{BHE} , or both = V_{IL} . $CE2 = V_{IH}$.

13. WE is HIGH for Read cycle. 14. Address valid prior to or coincident with \overline{CE}_1 transition LOW and CE_2 transition HIGH.

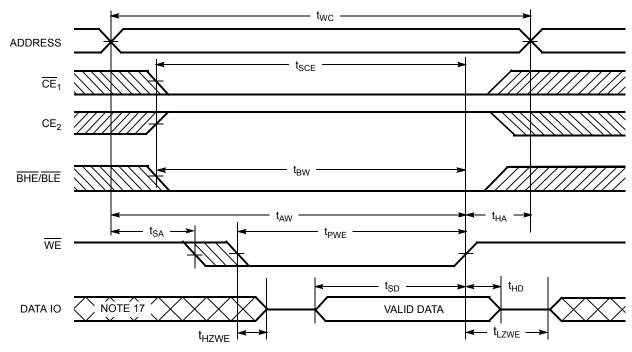


Switching Waveforms (continued)



Write Cycle No. 1 (\overline{CE}_1 or CE_2 Controlled) ^[15, 16]

Write Cycle No. 2 (WE Controlled, OE LOW) ^[15, 16]

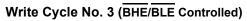


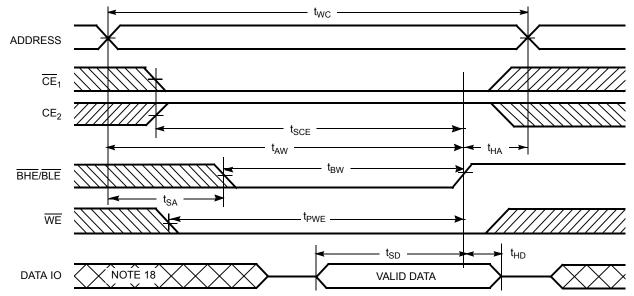
Notes

15. Data IO is high impedance if \overline{OE} , or \overline{BHE} or \overline{BLE} or both = V_{IH}. 16. If \overline{CE}_1 goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state. 17. During this period, the IOs are in output state and input signals should not be applied.



Switching Waveforms (continued)





Truth Table

CE ₁	CE ₂	OE	WE	BLE	BHE	I/O ₀ –I/O ₇	I/O ₈ –I/O ₁₅	Mode	Power
Н	Х	Х	Х	Х	Х	High Z	High Z	Power Down	Standby (I _{SB})
Х	L	Х	Х	Х	Х	High Z	High Z	Power Down	Standby (I _{SB})
L	Н	L	Н	L	L	Data Out	Data Out	Read All Bits	Active (I _{CC})
L	Н	L	Н	L	Н	Data Out	High Z	Read Lower Bits Only	Active (I _{CC})
L	Н	L	Н	Н	L	High Z	Data Out	Read Upper Bits Only	Active (I _{CC})
L	Н	Х	L	L	L	Data In	Data In	Write All Bits	Active (I _{CC})
L	Н	Х	L	L	Н	Data In	High Z	Write Lower Bits Only	Active (I _{CC})
L	Н	Х	L	Н	L	High Z	Data In	Write Upper Bits Only	Active (I _{CC})
L	Н	Н	Н	Х	Х	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})

Note 18. During this period, the IOs are in output state and input signals should not be applied.



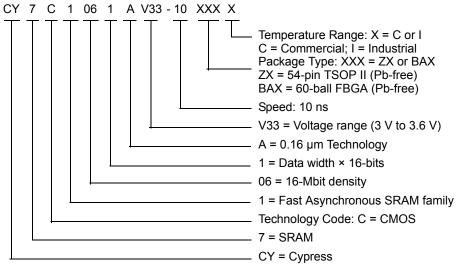


Ordering Information

The following table lists the CY7C1061AV33 key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products.

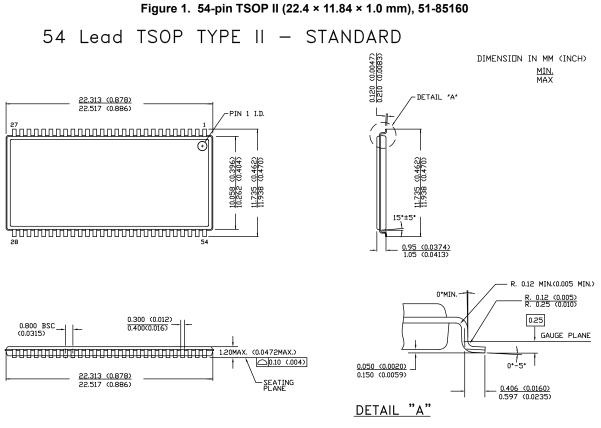
Speed (ns)	(ns) Ordering Code Package Diagram		Package Type	Operating Range
10	CY7C1061AV33-10ZXC	51-85160	54-pin TSOP II (Pb-free)	Commercial
	CY7C1061AV33-10ZXI	51-85160	54-pin TSOP II (Pb-free)	Industrial
	CY7C1061AV33-10BAXI	51-85162	60-ball FBGA (Pb-free)	

Ordering Code Definitions





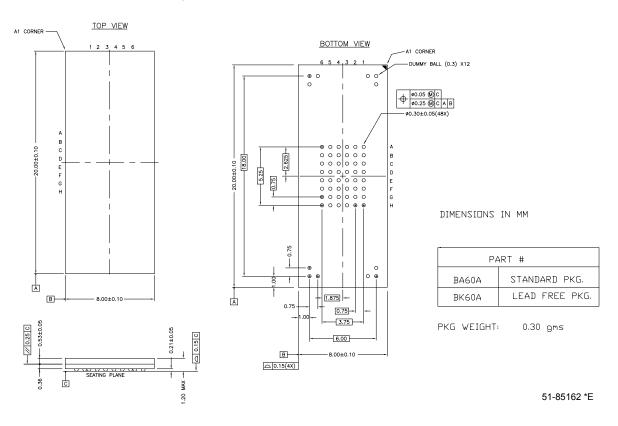
Package Diagrams



51-85160 *A



Package Diagrams (continued)







Acronyms

Acronym	Description		
CMOS	complementary metal oxide semiconductor		
FBGA	fine-pitch ball grid array		
I/O	input/output		
OE	output enable		
SRAM	static random access memory		
TSOP	thin small-outline package		
TTL	transistor-transistor logic		
WE	Write Enable		

Document Conventions

Units of Measure

Symbol	Unit of Measure	
ns	nano seconds	
V	Volts	
μA	micro Amperes	
mA	milli Amperes	
mm	milli meter	
ms	milli seconds	
MHz	Mega Hertz	
pF	pico Farad	
mW	milli Watts	
W	Watts	
°C	degree Celcius	
Ω	ohms	
%	percent	





Document History Page

Revision	ECN	Submission Date	Orig. of Change	Description of Change
**	113725	03/28/02	NSL	New Data Sheet
*A	117058	07/31/02	DFP	Removed 15-ns bin
*В	117989	08/30/02	DFP	Added 8-ns bin Changed lcc for 8, 10, 12 bins t_{power} changed from 1 µs to 1 ms. Load Cap Comment changed (for Tx line load) t_{SD} changed to 5.5 ns for the 10-ns bin Changed some 8-ns bin numbers (t_{HZ} , t_{DOE} , t_{DBE}) Removed hz <lz comments="" data="" from="" sheet<="" td=""></lz>
*C	120383	11/06/02	DFP	Final data sheet Added note 3 to "AC Test Loads and Waveforms" and note 7 to t_{pu} and t_{pd} Updated Input/Output Caps (for 48BGA only) to 8 pF/10 pF and for the 54-pin TSOP to 6/8 pF
*D	124439	2/25/03	MEG	Changed ISB1 from 100 mA to 70 mA Shaded fBGA production ordering information
*E	492137	See ECN	NXR	Corrected Block Diagram on page #1 Removed 8 ns speed bin Changed 48-Ball FBGA to 60-Ball FBGA in Pin Configuration Included Note #1 and 2 on page #2 Changed the description of I _{IX} from Input Load Current to Input Leakage Current in DC Electrical Characteristics table Updated the Ordering Information Table
*F	508117	See ECN	NXR	Updated FBGA Pin Configuration Updated Ordering Information table
*G	877322	See ECN	VKN	Updated Ordering Information table
*H	2897049	03/22/10	KAO	Removed inactive parts from the ordering information table. Updated package diagrams, links in Sales, Solutions and Legal Information
*	3109147	12/13/2010	KAO	Added Ordering Code Definitions.
*J	3160428	02/02/11	PRAS	Ordering information updates. Template and style updates.
*K	3222127	04/11/2011	PRAS	Added Acronyms and Units of Measure.



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